# 8-Bit Serial-Input/Serial or Parallel-Output Shift Register with Latched 3-State Outputs

High-Performance Silicon-Gate CMOS

# **MC74HC595A**

The MC74HC595A consists of an 8-bit shift register and an 8-bit D-type latch with three-state parallel outputs. The shift register accepts serial data and provides a serial output. The shift register also provides parallel data to the 8-bit latch. The shift register and latch have independent clock inputs. This device also has an asynchronous reset for the shift register.

The HC595A directly interfaces with the SPI serial data port on CMOS MPUs and MCUs.

### Features

- Output Drive Capability: 15 LSTTL Loads
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V
- Low Input Current: 1.0 μA
- High Noise Immunity Characteristic of CMOS Devices
- In Compliance with the Requirements Defined by JEDEC Standard No. 7 A
- Chip Complexity: 328 FETs or 82 Equivalent Gates
- Improvements over HC595
  - Improved Propagation Delays
  - ◆ 50% Lower Quiescent Power
  - Improved Input Noise and Latchup Immunity
- NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free and are RoHS Compliant



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SOIC-16 D SUFFIX CASE 751B

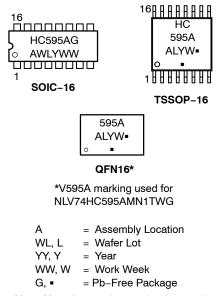


DT SUFFIX CASE 948F



QFN16 MN SUFFIX CASE 485AW

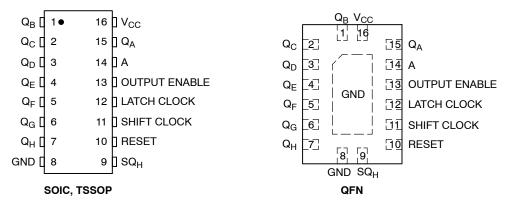
MARKING DIAGRAMS



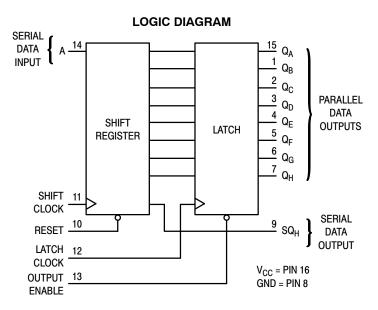
(Note: Microdot may be in either location)

### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 11 of this data sheet.







### MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)	-0.5 to +7.0	V
V <sub>in</sub>	DC Input Voltage (Referenced to GND)	–0.5 to V <sub>CC</sub> +0.5	V
V <sub>out</sub>	DC Output Voltage (Referenced to GND)	–0.5 to V <sub>CC</sub> +0.5	V
l <sub>in</sub>	DC Input Current, per Pin	±20	mA
l <sub>out</sub>	DC Output Current, per Pin	±35	mA
I <sub>CC</sub>	DC Supply Current, V <sub>CC</sub> and GND Pins	±75	mA
P <sub>D</sub>	Power Dissipation in Still Air, SOIC Package† TSSOP Package†	500 450	mW
T <sub>stg</sub>	Storage Temperature	–65 to +150	°C
TL	Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP, SOIC or TSSOP Package)	260	°C
V <sub>ESD</sub>	ESD Withstand Voltage Human Body Model (Note 1) Machine Model (Note 2) Charged Device Model (Note 3)	> 3000 > 400 N/A	V

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range GND  $\leq (V_{in} \text{ or } V_{out}) \leq V_{CC}$ .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or  $V_{CC}$ ). Unused outputs must be left open.

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

†Derating: SOIC Package: -7 mW/°C from 65° to 125°C

TSSOP Package: -6.1 mW/°C from 65° to 125°C

1. Tested to EIA/JESD22–A114–A.

Tested to EIA/JESD22-A115-A.
Tested to JESD22-C101-A.

### 3. Tested to 3E3D22-0101-A.

### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit	
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)		2.0	6.0	V
V <sub>in</sub> , V <sub>out</sub>	DC Input Voltage, Output Voltage (Referenced to GND)	0	V <sub>CC</sub>	V	
T <sub>A</sub>	Operating Temperature, All Package Types		-55	+125	°C
t <sub>r</sub> , t <sub>f</sub>	(Figure 1) V <sub>C</sub>	<sub>C</sub> = 2.0 V <sub>C</sub> = 4.5 V <sub>C</sub> = 6.0 V	0 0 0	1000 500 400	ns

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

				V <sub>cc</sub>	Guar	anteed Lim	it	
Symbol	Parameter	Test Cond	v	–55 to 25°C	≤ <b>85</b> ° <b>C</b>	≤ 125°C	Uni	
V <sub>IH</sub>	Minimum High–Level Input Voltage	$\label{eq:Vout} \begin{array}{l} V_{out} = 0.1 \ V \ or \ V_{CC} - 0.1 \ V \\  I_{out}  \leq 20 \ \mu A \end{array}$		2.0 3.0 4.5 6.0	1.5 2.1 3.15 4.2	1.5 2.1 3.15 4.2	1.5 2.1 3.15 4.2	V
V <sub>IL</sub>	Maximum Low-Level Input Voltage	$\label{eq:Vout} \begin{split} V_{out} &= 0.1 \text{ V or } V_{CC} \\  I_{out}  &\leq 20 \ \mu\text{A} \end{split}$	– 0.1 V	2.0 3.0 4.5 6.0	0.5 0.9 1.35 1.8	0.5 0.9 1.35 1.8	0.5 0.9 1.35 1.8	V
V <sub>OH</sub>	Minimum High–Level Output Voltage, Q <sub>A</sub> – Q <sub>H</sub>	$V_{in} = V_{IH} \text{ or } V_{IL}$ $ I_{out}  \le 20 \ \mu A$		2.0 4.5 6.0	1.9 4.4 5.9	1.9 4.4 5.9	1.9 4.4 5.9	V
		$V_{in} = V_{IH} \text{ or } V_{IL}$	$\begin{split}  I_{out}  &\leq 2.4 \text{ mA} \\  I_{out}  &\leq 6.0 \text{ mA} \\  I_{out}  &\leq 7.8 \text{ mA} \end{split}$	3.0 4.5 6.0	2.48 3.98 5.48	2.34 3.84 5.34	2.2 3.7 5.2	
V <sub>OL</sub>	Maximum Low–Level Output Voltage, Q <sub>A</sub> – Q <sub>H</sub>	$V_{in} = V_{IH} \text{ or } V_{IL}$ $ I_{out}  \le 20 \ \mu A$		2.0 4.5 6.0	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V
		$V_{in} = V_{IH} \text{ or } V_{IL}$	$\begin{split}  I_{out}  &\leq 2.4 \text{ mA} \\  I_{out}  &\leq 6.0 \text{ mA} \\  I_{out}  &\leq 7.8 \text{ mA} \end{split}$	3.0 4.5 6.0	0.26 0.26 0.26	0.33 0.33 0.33	0.4 0.4 0.4	
V <sub>OH</sub>	Minimum High–Level Output Voltage, SQ <sub>H</sub>	$\label{eq:Vin} \begin{split} V_{in} &= V_{IH} \text{ or } V_{IL} \\ II_{out} I &\leq 20 \ \mu A \end{split}$		2.0 4.5 6.0	1.9 4.4 5.9	1.9 4.4 5.9	1.9 4.4 5.9	V
		$V_{in} = V_{IH} \text{ or } V_{IL}$	$\begin{split}  I_{out}  &\leq 2.4 \text{ mA} \\  I_{out}  &\leq 4.0 \text{ mA} \\  I_{out}  &\leq 5.2 \text{ mA} \end{split}$	3.0 4.5 6.0	2.48 3.98 5.48	2.34 3.84 5.34	2.2 3.7 5.2	
V <sub>OL</sub>	Maximum Low-Level Output Voltage, SQ <sub>H</sub>	$V_{in} = V_{IH} \text{ or } V_{IL}$ $II_{out}I \le 20 \ \mu A$		2.0 4.5 6.0	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V
		$V_{in} = V_{IH} \text{ or } V_{IL}$	$\begin{split}  I_{out}  &\leq 2.4 \text{ mA} \\  I_{out}  &\leq 4.0 \text{ mA} \\  I_{out}  &\leq 5.2 \text{ mA} \end{split}$	3.0 4.5 6.0	0.26 0.26 0.26	0.33 0.33 0.33	0.4 0.4 0.4	
l <sub>in</sub>	Maximum Input Leakage Current	$V_{in} = V_{CC}$ or GND		6.0	±0.1	±1.0	±1.0	μA
I <sub>OZ</sub>	Maximum Three-State Leakage Current, Q <sub>A</sub> – Q <sub>H</sub>	$\begin{array}{l} \text{Output in High-Imp} \\ \text{V}_{in} = \text{V}_{IL} \text{ or } \text{V}_{IH} \\ \text{V}_{out} = \text{V}_{CC} \text{ or } \text{GND} \end{array}$		6.0	±0.5	±5.0	±10	μA
I <sub>CC</sub>	Maximum Quiescent Supply Current (per Package)	$V_{in} = V_{CC} \text{ or } GND$ $I_{out} = 0 \ \mu A$		6.0	4.0	40	160	μA

		V <sub>CC</sub>	Guaranteed Limit			
Symbol	Parameter	v	–55 to 25°C	≤ 85°C	≤ 125°C	Unit
f <sub>max</sub>	Maximum Clock Frequency (50% Duty Cycle)	2.0	6.0	4.8	4.0	MH
max	(Figures 1 and 7)	3.0	15	10	8.0	
	, <u>-</u> ,	4.5	30	24	20	
		6.0	35	28	24	
t <sub>PLH</sub> ,	Maximum Propagation Delay, Shift Clock to SQ <sub>H</sub>	2.0	140	175	210	ns
t <sub>PHL</sub>	(Figures 1 and 7)	3.0	100	125	150	
		4.5	28	35	42	
		6.0	24	30	36	
t <sub>PHL</sub>	Maximum Propagation Delay, Reset to SQ <sub>H</sub>	2.0	145	180	220	ns
	(Figures 2 and 7)	3.0	100	125	150	
		4.5	29	36	44	
		6.0	25	31	38	
t <sub>PLH</sub> ,	Maximum Propagation Delay, Latch Clock to Q <sub>A</sub> – Q <sub>H</sub>	2.0	140	175	210	ns
t <sub>PHL</sub>	(Figures 3 and 7)	3.0	100	125	150	
		4.5	28	35	42	
		6.0	24	30	36	
t <sub>PLZ</sub> ,	Maximum Propagation Delay, Output Enable to Q <sub>A</sub> – Q <sub>H</sub>	2.0	150	190	225	ns
t <sub>PHZ</sub>	(Figures 4 and 8)	3.0	100	125	150	
		4.5	30	38	45	
		6.0	26	33	38	
t <sub>PZL</sub> ,	Maximum Propagation Delay, Output Enable to Q <sub>A</sub> – Q <sub>H</sub>	2.0	135	170	205	ns
t <sub>PZH</sub>	(Figures 4 and 8)	3.0	90	110	130	
		4.5	27	34	41	
		6.0	23	29	35	
t <sub>TLH</sub> ,	Maximum Output Transition Time, Q <sub>A</sub> – Q <sub>H</sub>	2.0	60	75	90	ns
t <sub>THL</sub>	(Figures 3 and 7)	3.0	23	27	31	
		4.5	12	15	18	
		6.0	10	13	15	
t <sub>TLH</sub> ,	Maximum Output Transition Time, SQ <sub>H</sub>	2.0	75	95	110	ns
t <sub>THL</sub>	(Figures 1 and 7)	3.0	27	32	36	
		4.5	15	19	22	
		6.0	13	16	19	
C <sub>in</sub>	Maximum Input Capacitance	-	10	10	10	pF
Cout	Maximum Three-State Output Capacitance (Output in	-	15	15	15	pF
	High-Impedance State), Q <sub>A</sub> - Q <sub>H</sub>					
			Typical @	25°C, V <sub>CC</sub>	= 5.0 V	

300

pF

# AC ELECTRICAL CHARACTERISTICS ( $C_L$ = 50 pF, Input $t_r$ = $t_f$ = 6.0 ns)

Power Dissipation Capacitance (Per Package)\*

 $C_{\text{PD}}$ 

### **TIMING REQUIREMENTS** (Input $t_r = t_f = 6.0 \text{ ns}$ )

		v <sub>cc</sub>	Guara	anteed Limi	it	
Symbol	Parameter	V	25°C to -55°C	≤ 85°C	≤ 125°C	Unit
t <sub>su</sub>	Minimum Setup Time, Serial Data Input A to Shift Clock	2.0	50	65	75	ns
	(Figure 5)	3.0	40	50	60	
		4.5	10	13	15	
		6.0	9.0	11	13	
t <sub>su</sub>	Minimum Setup Time, Shift Clock to Latch Clock	2.0	75	95	110	ns
	(Figure 6)	3.0	60	70	80	
		4.5	15	19	22	
		6.0	13	16	19	
t <sub>h</sub>	Minimum Hold Time, Shift Clock to Serial Data Input A	2.0	5.0	5.0	5.0	ns
	(Figure 5)	3.0	5.0	5.0	5.0	
		4.5	5.0	5.0	5.0	
		6.0	5.0	5.0	5.0	
t <sub>rec</sub>	Minimum Recovery Time, Reset Inactive to Shift Clock	2.0	50	65	75	ns
	(Figure 2)	3.0	40	50	60	
		4.5	10	13	15	
		6.0	9.0	11	13	
tw	Minimum Pulse Width, Reset	2.0	60	75	90	ns
	(Figure 2)	3.0	45	60	70	
		4.5	12	15	18	
		6.0	10	13	15	
tw	Minimum Pulse Width, Shift Clock	2.0	50	65	75	ns
	(Figure 1)	3.0	40	50	60	
		4.5	10	13	15	
		6.0	9.0	11	13	
tw	Minimum Pulse Width, Latch Clock	2.0	50	65	75	ns
	(Figure 6)	3.0	40	50	60	
		4.5	10	13	15	
		6.0	9.0	11	13	
t <sub>r</sub> , t <sub>f</sub>	Maximum Input Rise and Fall Times	2.0	1000	1000	1000	ns
	(Figure 1)	3.0	800	800	800	
		4.5	500	500	500	
		6.0	400	400	400	

FUNCTION TABL	E
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Inputs				Resulting Function					
Operation	Reset	Serial Input A	Shift Clock	Latch Clock	Output Enable	Shift Register Contents	Latch Register Contents	Serial Output SQ <sub>H</sub>	Parallel Outputs Q <sub>A</sub> – Q <sub>H</sub>
Reset shift register	L	Х	Х	L, H, ↓	L	L	U	L	U
Shift data into shift register	Н	D	↑	L, H, ↓	L	$\begin{array}{c} D \rightarrow SR_{A};\\ SR_{N} \rightarrow SR_{N+1} \end{array}$	U	$\text{SR}_{\text{G}} {\rightarrow} \text{SR}_{\text{H}}$	U
Shift register remains unchanged	Н	Х	L, H, ↓	L, H, ↓	L	U	U	U	U
Transfer shift register contents to latch register	Н	X	L, H, ↓	Ŷ	L	U	$SR_N \to LR_N$	U	SR <sub>N</sub>
Latch register remains unchanged	Х	Х	х	L, H, ↓	L	*	U	*	U
Enable parallel outputs	Х	Х	Х	Х	L	*	**	*	Enabled
Force outputs into high impedance state	х	Х	Х	Х	Н	*	**	*	Z

LR = latch register contents

U = remains unchanged

 $\downarrow$  = High-to-Low

\* = depends on Reset and Shift Clock inputs
\*\* = depends on Latch Clock input

### **PIN DESCRIPTIONS**

### INPUTS

### A (Pin 14)

Serial Data Input. The data on this pin is shifted into the 8-bit serial shift register.

# CONTROL INPUTS

Shift Clock (Pin 11)

Shift Register Clock Input. A low– to–high transition on this input causes the data at the Serial Input pin to be shifted into the 8–bit shift register.

### Reset (Pin 10)

Active–low, Asynchronous, Shift Register Reset Input. A low on this pin resets the shift register portion of this device only. The 8–bit latch is not affected.

### Latch Clock (Pin 12)

Storage Latch Clock Input. A low-to-high transition on this input latches the shift register data.

### Output Enable (Pin 13)

Active-low Output Enable. A low on this input allows the data from the latches to be presented at the outputs. A high on this input forces the outputs  $(Q_A-Q_H)$  into the high-impedance state. The serial output is not affected by this control unit.

### OUTPUTS

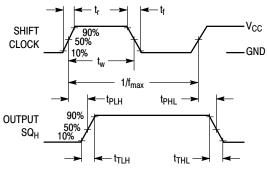
### $Q_A - Q_H$ (Pins 15, 1, 2, 3, 4, 5, 6, 7)

Noninverted, 3-state, latch outputs.

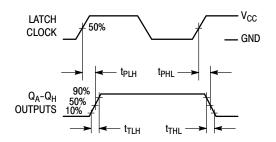
### SQ<sub>H</sub> (Pin 9)

Noninverted, Serial Data Output. This is the output of the eighth stage of the 8-bit shift register. This output does not have three-state capability.

### SWITCHING WAVEFORMS









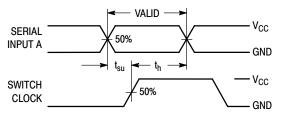
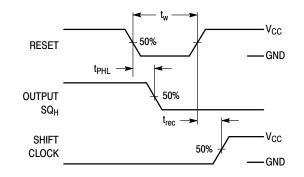
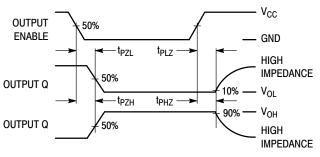


Figure 5.









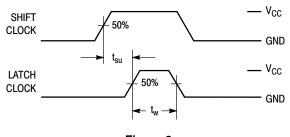
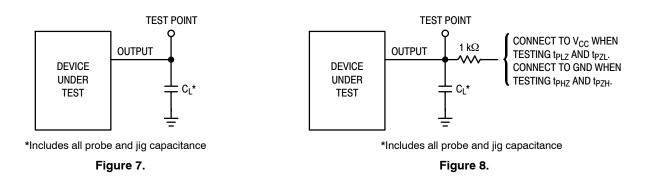
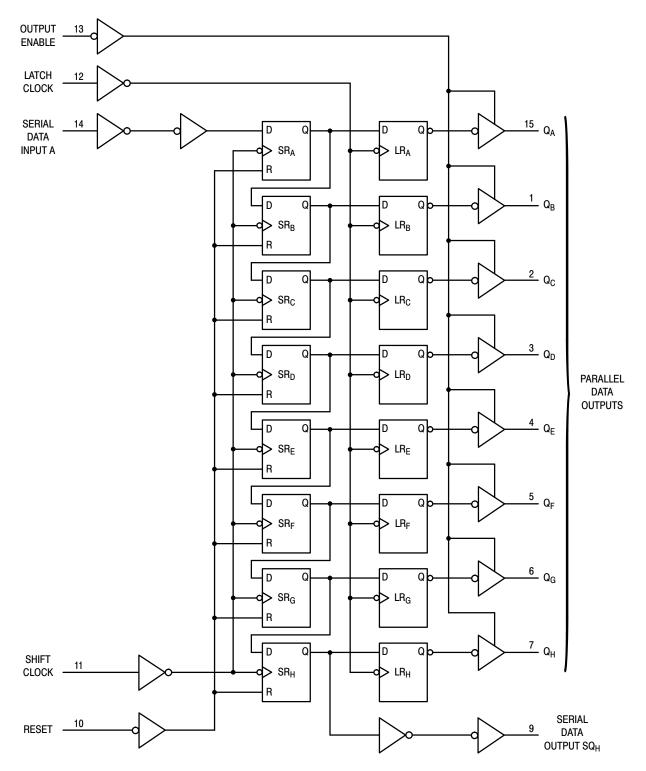


Figure 6.

### **TEST CIRCUITS**



### EXPANDED LOGIC DIAGRAM



	TIMING DIAGRAM
SHIFT CLOCK	
SERIAL DATA INPUT A	
RESET	
LATCH CLOCK	
output Enable	
Q <sub>A</sub>	
Q <sub>B</sub>	
Q <sub>C</sub>	
QD	
$Q_E$	
Q <sub>F</sub>	
$Q_G$	
Q <sub>H</sub>	
SERIAL DATA OUTPUT SQ <sub>H</sub>	
	NOTE: XXX implies that the output is in a high-impedance state.

### **ORDERING INFORMATION**

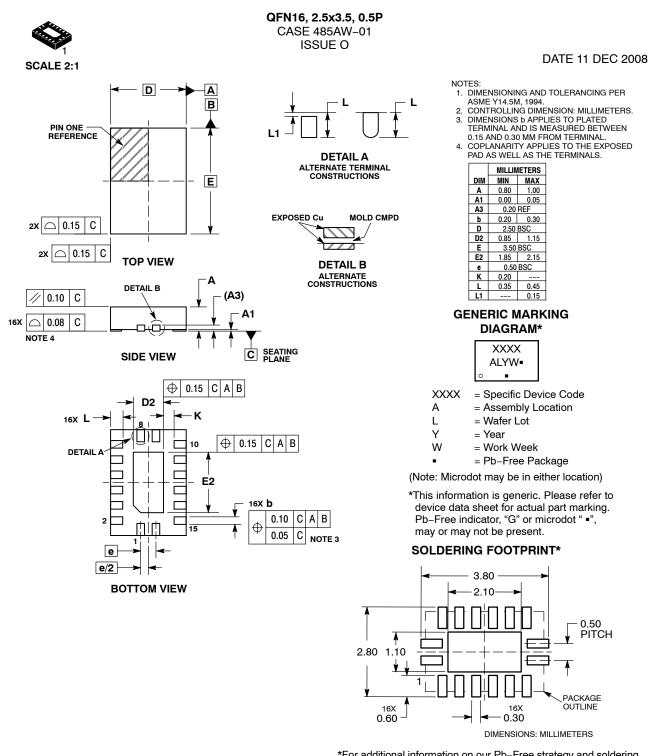
Device	Package	Shipping <sup>†</sup>
MC74HC595ADG		48 Units / Rail
NLV74HC595ADG*		48 Units / Rail
MC74HC595ADR2G	SOIC-16	2500 / Tape & Reel
NLV74HC595ADR2G*	(Pb-Free)	2500 / Tape & Reel
MC74HC595AADR2G		2500 / Tape & Reel
NLV74HC595AADR2G* (Contact ON Semiconductor)		2500 / Tape & Reel
MC74HC595ADTG		96 Units / Tube
NLV74HC595ADTG*		96 Units / Tube
MC74HC595ADTR2G	TSSOP-16 (Pb-Free)	2500 / Tape & Reel
NLV74HC595ADTR2G*		2500 / Tape & Reel
NLV74HC595AADTR2G*		2500 / Tape & Reel
MC74HC595AMNTWG#		3000 / Tape & Reel
NLV74HC595AMNTWG*#	QFN16 (Pb-Free)	3000 / Tape & Reel
NLV74HC595AMN1TWG*#		3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

\*NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable.

#MN suffix is with pull-back lead, MN1 is without pull-back lead. Refer to 'Detail A' of case outline on page 13.





\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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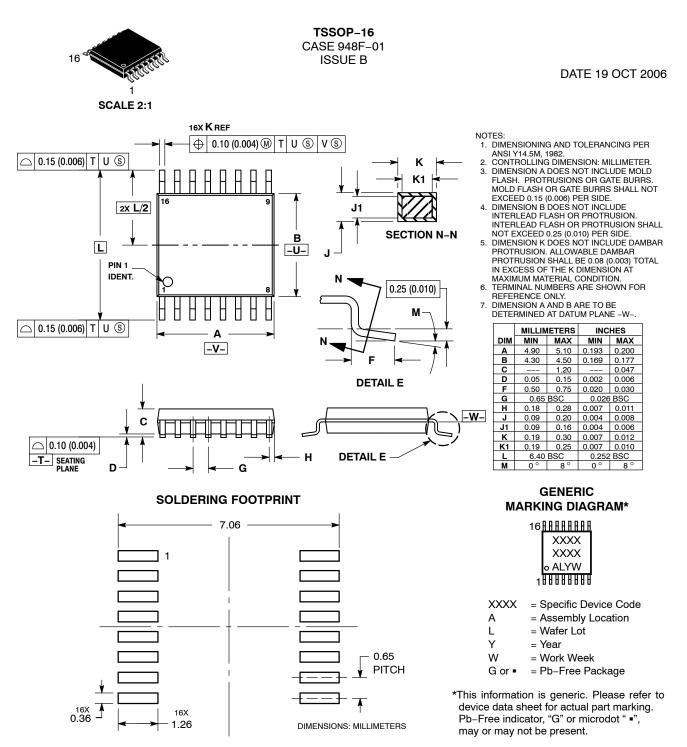


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